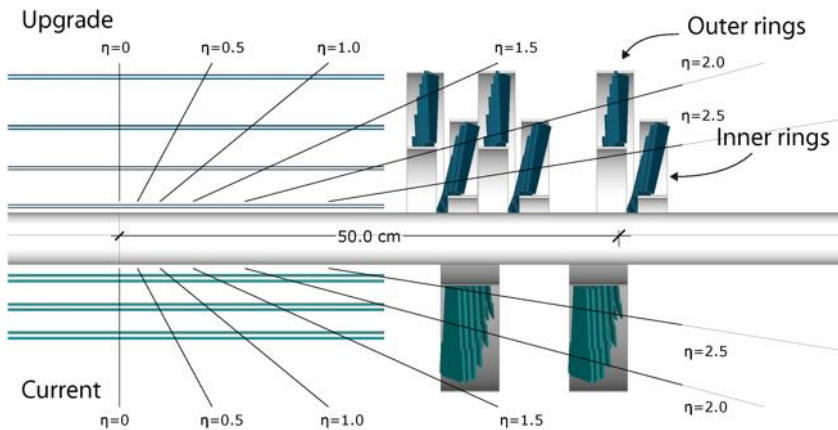




Pixel, tracking e b-tagging 2017

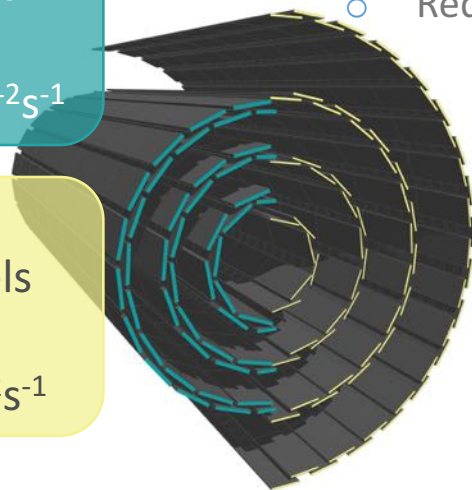
A. ROSSI



- Requirements for the new detector
 - No bandwidth limit and reduced dynamic inefficiency up to $PU \sim 110$: **beyond** $L \sim 2 * 10^{34} \text{ cm}^{-2} \text{ s}^{-1}$
 - Layer 1 closer to the beam pipe: 4.4 cm \rightarrow 2.9 cm
 - 4 layers and 3+3 disks
 - Fully functional up to LS3
 - New ASICs
 - PS146dig (BPIX L2-L4, FPIX): larger buffers, digital data transmission
 - PROC600 (BPIX L1): different double column readout
 - New DAQ system
 - Reduced material: CO2 cooling, DCDC converters

Old detector
 1444 modules – 66M pixels
 $R \sim 4.4 \text{ cm}$
 $150 \text{ MHz/cm}^2 @ 1.4 \times 10^{34} \text{ cm}^{-2} \text{ s}^{-1}$

New detector
 1760 modules – 117M pixels
 $R \sim 2.9 \text{ cm}$
 $580 \text{ MHz/cm}^2 @ 2 \times 10^{34} \text{ cm}^{-2} \text{ s}^{-1}$



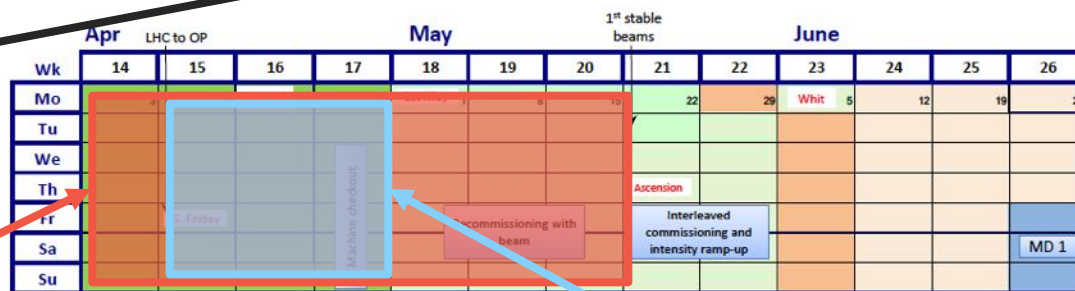
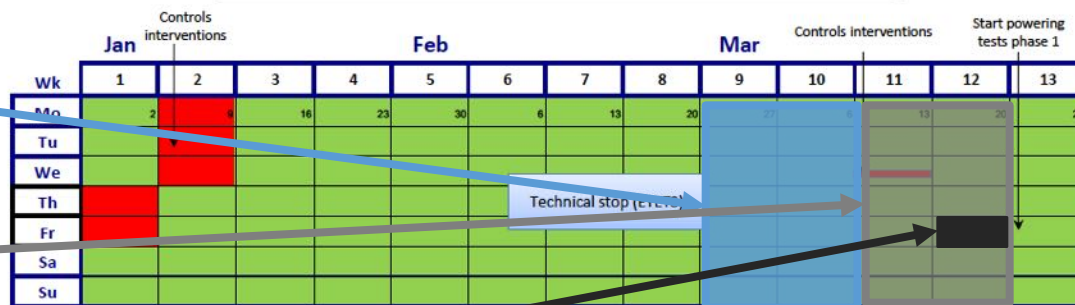
Installation and Commissioning



Detector Installation

Connection Checkout

Cooling plant running cold:
no problem → CMS can be closed



NEW (!!)

- ### Pixel detector commissioning:
- Phases readout and control links
 - New 400 MHz data links
 - Readout chip shaper tuning
 - Pulse height and gain tuning
 - Thresholds tuning
 - FPIX profited of pre-installation calibration
 - BPIX L1 with conservative thresholds

Cosmic runs:

- Verify detector(s) tuning
- DAQ in global runs with the whole detector(s)
- Coarse time alignment
- First space alignment
- **MAJOR RESULT: found and fixed a serious bug in the pixel geometry**

- Power delivered through on detector DCDC converters
 - 11-11.5V → 2.4-3.5 V
 - On-detector protection fuses will be removed during LS2
 - No incident in the detector...up to October 5th
 - Turned out to be ideal for the power cycles to recover modules affected SEUs
 - It is enough to disable/re-enable single DCDC converters
- CO₂ 2-phase cooling: a new entry in CMS
- Completely new DAQ system
 - New readout links: 400 MHz fully digital
 - New back end standard: uTCA
 - New back end boards: FEDs, FECs, AMC13
 - Bandwidth limit improved with respect to old detector: ~80 pileup events at 100 kHz
 - New f/w in development to go over PU=100 (Heavy Ions)

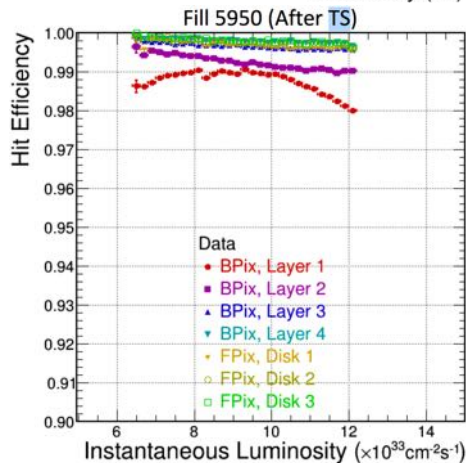
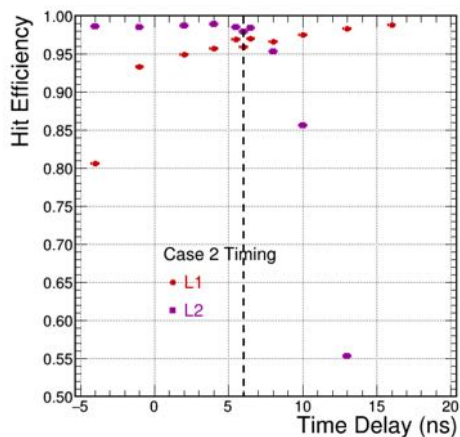
- PROC600 (BPIX L1) main source of problems
 - Rate-dependent cross-talk noise observed during module test
 - Thresholds set, conservatively higher than planned (~ 3000 - 4000 e $^-$). In time thresholds depend also on timing setting
 - Different clock phase w.r.t. PSI46dig (BPIX L2)
 - Not possible to choose optimal timing setting both for BPIX L1 and L2: observed with first collisions
 - Phase difference had to be corrected in the clock distribution circuits
 - Higher than expected dynamic inefficiency (rate-dependent data losses)
 - Exact cause(s) not yet understood fully
 - Several adjustments and studies done to mitigate and understand it
 - Larger spread in pixel signal gain and pedestals
 - Require careful pulse height tuning and high granularity offline corrections
 - Postponed during commissioning without beam and completed during TS1
- Observed “unrecoverable” SEUs in Token Bit Manager (TBM)
 - Mostly in BPIX L1 because of the higher particle rate
 - It requires a power cycle (DCDC converter dis/re-enabled)

Commissioning : Timing Scan

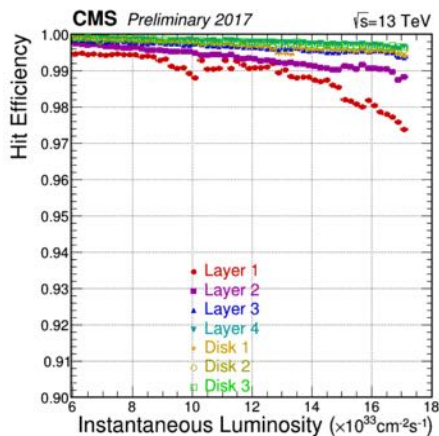
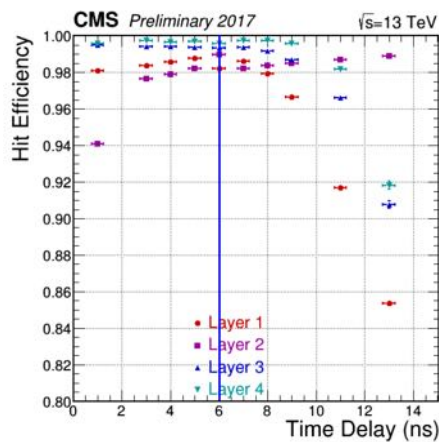


- Different approach tested in order to get the best performance from Bpix L1 and Bpix L2

2nd attempt: L1 early, L2 late



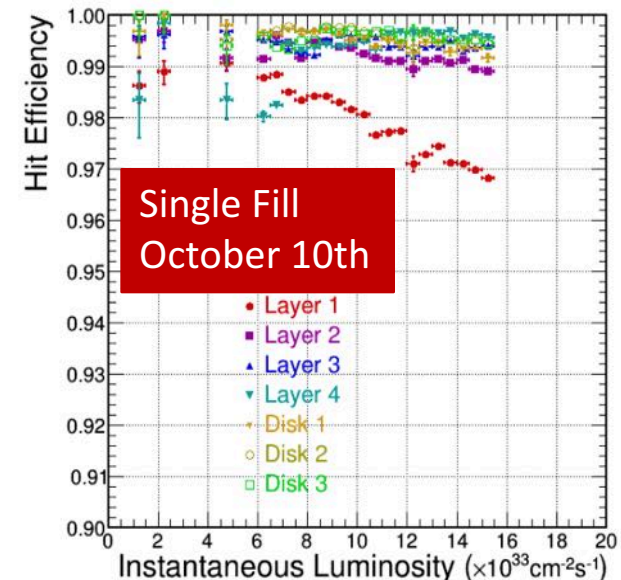
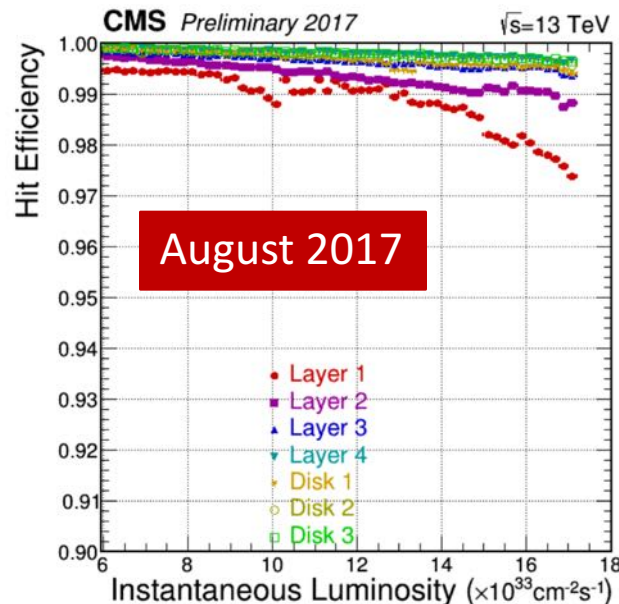
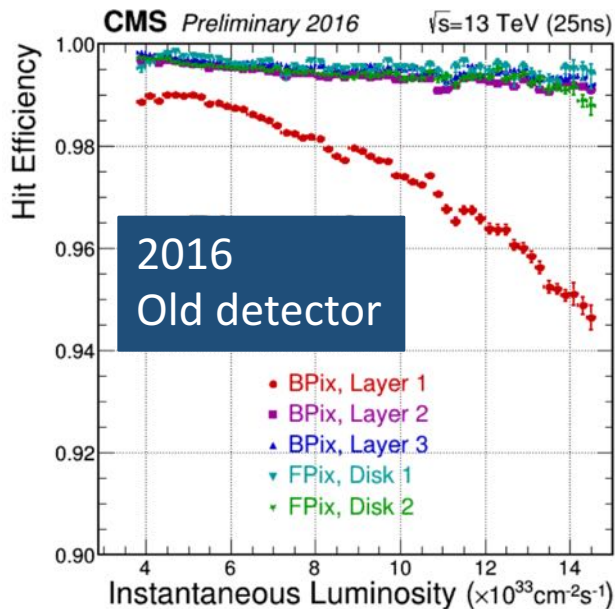
3rd attempt: L2 early, L1 late



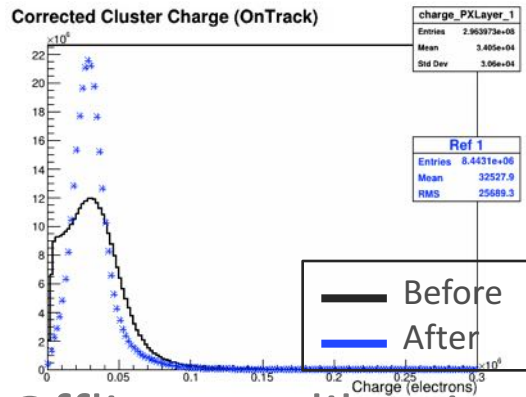
Final Settings:

- Not optimal for Bpix L2: threshold 1000e- higher than ideal one

- Dynamic inefficiency is smaller than in the old detector
- Expected to be even smaller
 - 98% at $2 \times 10^{34} \text{ cm}^{-2} \text{ s}^{-1}$
- Source not completely understood

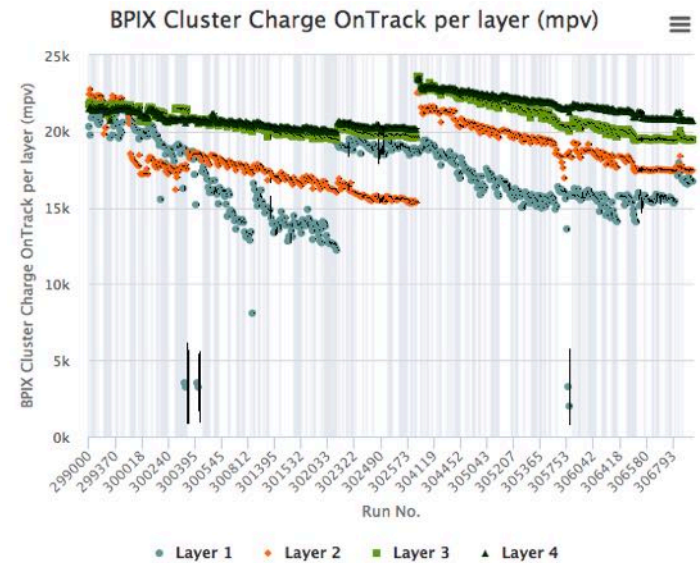
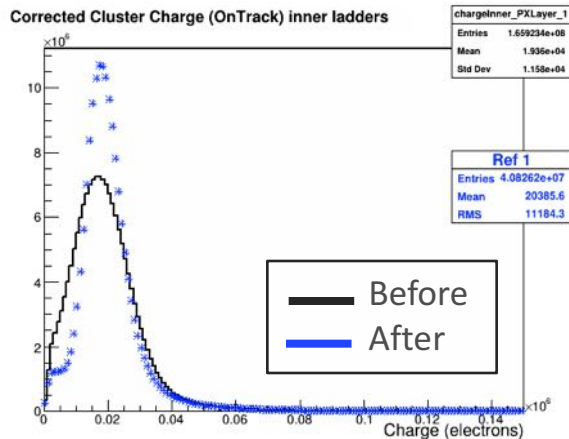


- i.e. : Cluster Charge
 - Pulse height and gain calibration

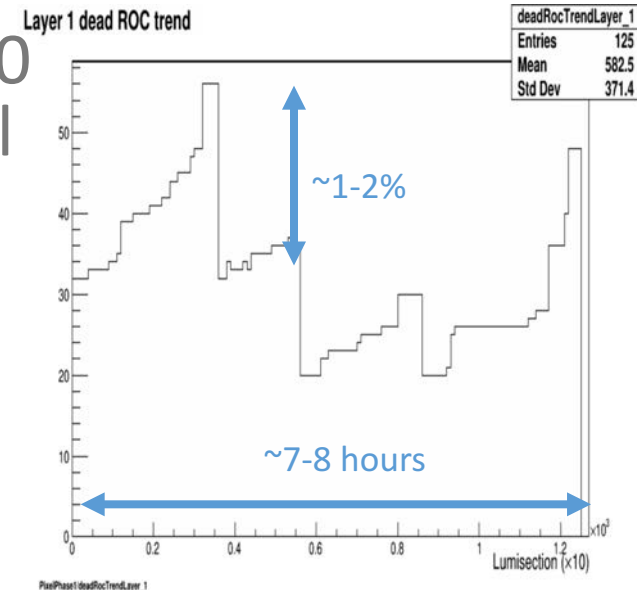


- HV increase recover steady signal loss

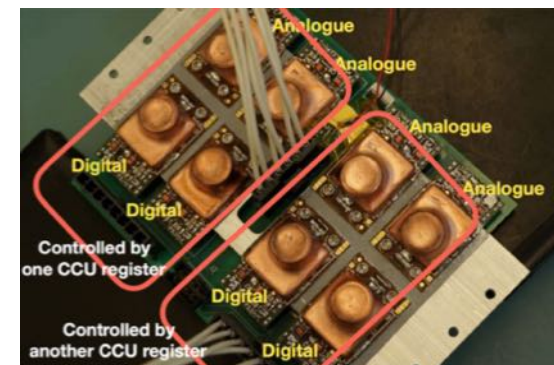
- Offline recalibration + Bug fix (ReReco)



- Single Event Upsets (SEUs) affect ROC, TBM and portcard
 - ~2ROC (1/8 module) inactive every 10 minutes at $L \sim 10^{34} \text{cm}^{-2}\text{s}^{-1}$
 - Mainly on Bpix Layer1
 - Some SEUs on TBM are not recover with a reset (“stuck” TBM)
 - power cycle needed
- Automatically masked without affecting data taking
- Soft Error Recovery attempted when 20 channels affected (15 in L1, 8 in central L1)
 - Firstly by reprogramming the modules
 - Modules not recovered at first attempt are power cycled
 - SEUs in port cards (~10 modules) are detected and recovered by reprogramming



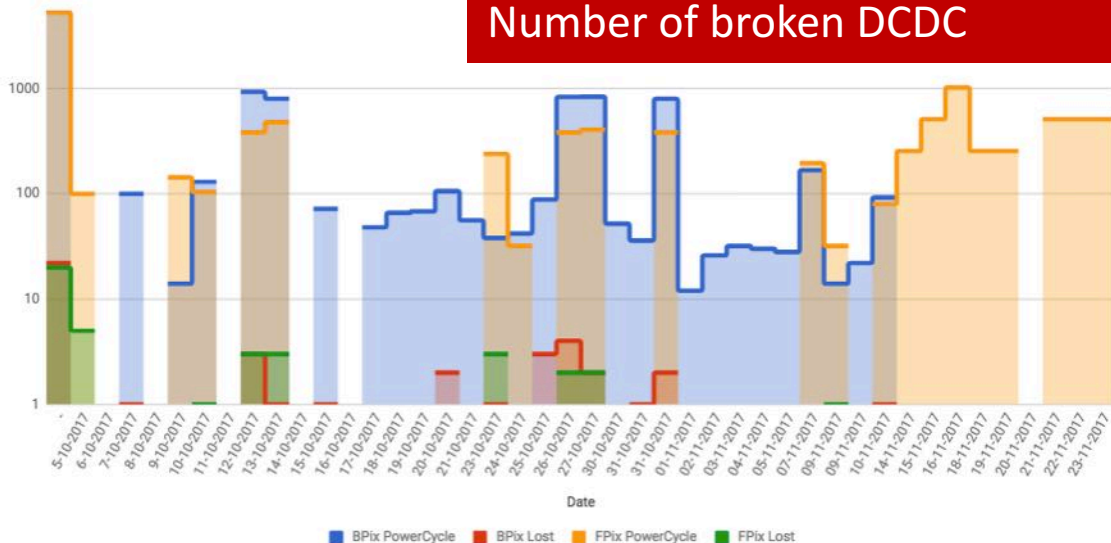
- DCDC stop working without (apparently) no reason
- First event on October 5th
- Almost all of them after a dis/en-able cycle or a power cycle
 - Only one hours after the last power cycle and one during stable beams
- Both digital (3.3/3.5V) and analog (2.4V) DCDC converters are affected
- Both Bpix and Fpix
- Power cycle or dis/en-able many of them in any case
 - to recover modules affected by the “unrecoverable” SEUs in the TBM
 - To investigate the problem
 - Because of global power cycles of the detector
 - LHC and beam conditions
- Failures almost continuously up to now
 - Rate slightly decrease in the last 2 weeks



- Task Force in place
 - <https://twiki.cern.ch/twiki/bin/view/CMS/PixelPowerProblems>
- Daily Pixel Operation meeting :
<https://indico.cern.ch/category/1732/>
- Technical Incident Panel
 - <https://indico.cern.ch/event/677774/>
- Explanation and solution not yet found

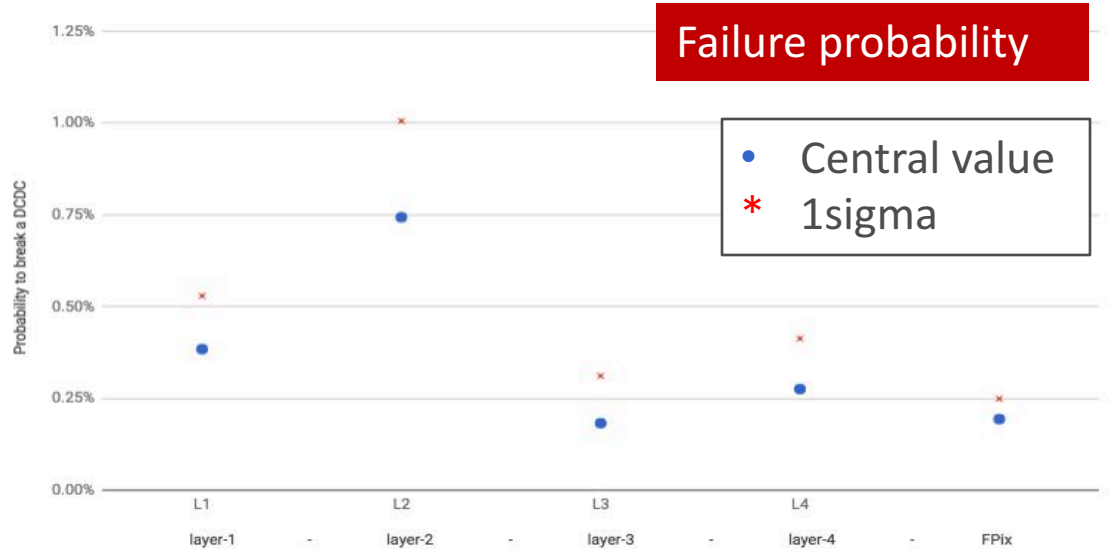
BPix PC, BPix Lost, FPix PC e FPix Lost

Number of DCDC powercycled
Number of broken DCDC



- All DCDC power cycle from October 5th
 - Manual dis/en-abling to recover "stuck TBM"
 - Full detector power cycle (5)
 - Fpix D1+D3 massive power cycles (10)
 - Automatic PC
 - Re-enable for few hours

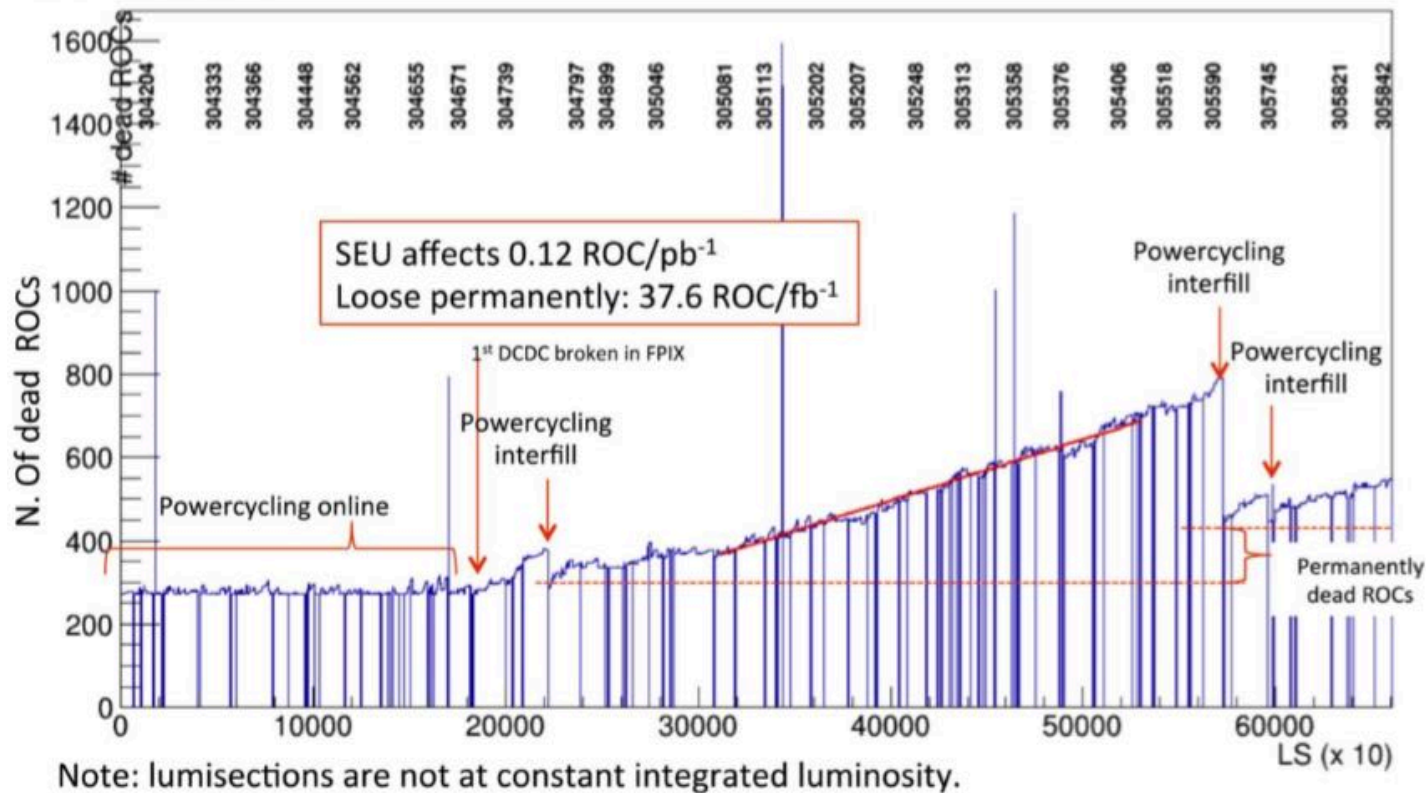
Failure probability

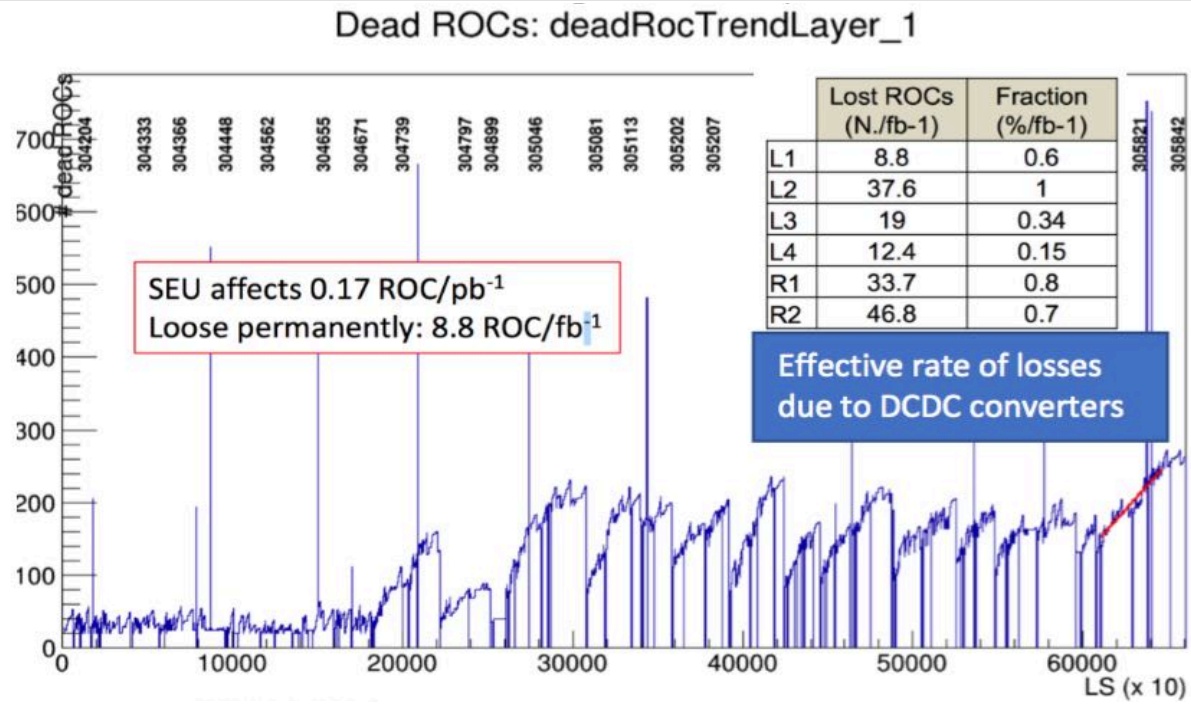


- 55 DCDC converter failures
 - **Few of them restart to work (spontaneously)**
 - 5 Analog, 4 Digital
 - 3 unstable
 - 2 provide limited analog current

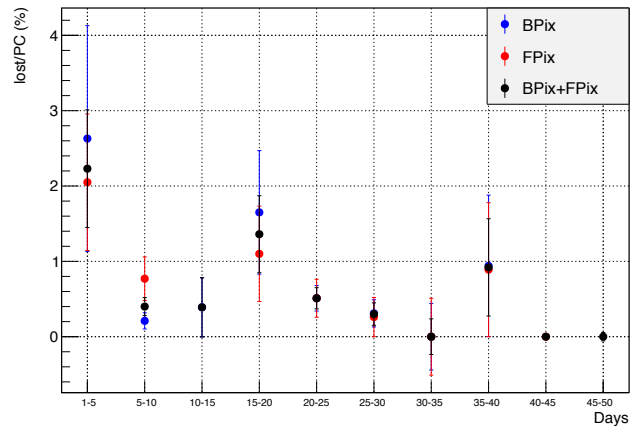
- Inactive channels build up because of “stuck TBM” and no automatic power cycle
- Interfill power cycles recover them but can break DCDC converters
 - DCDC failure proportional to luminosity

Bpix Layer 2





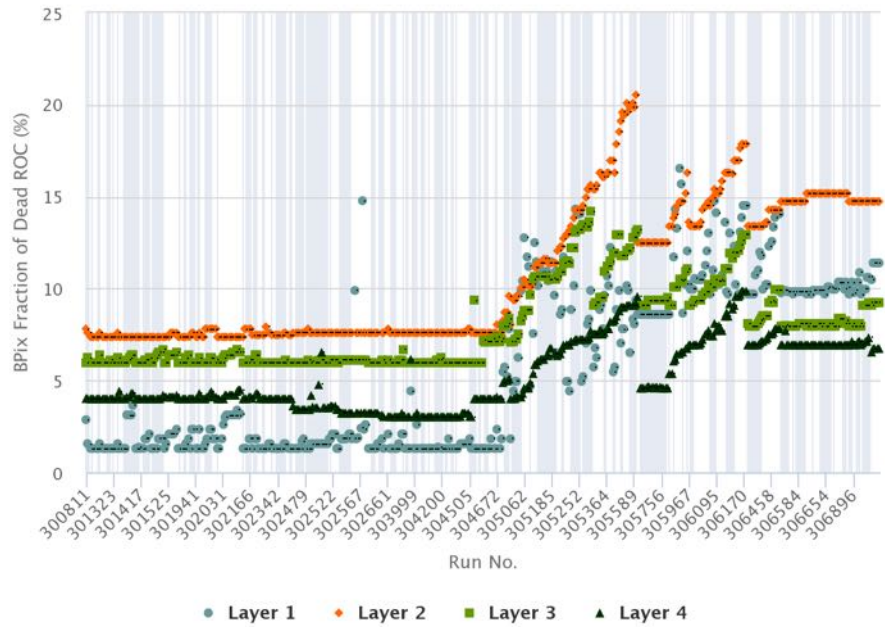
Probability to lose a DCDC (in bins of 5 days)



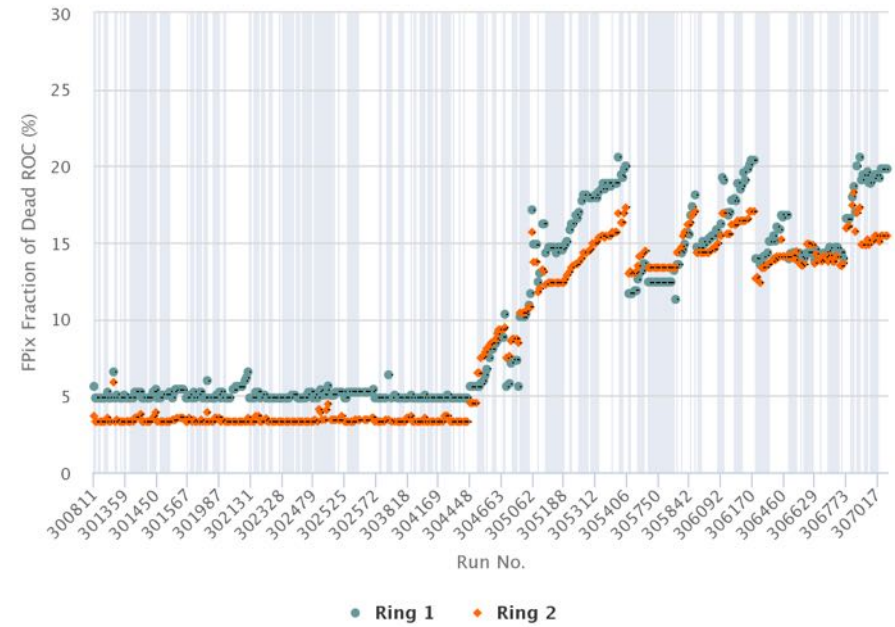
- During the last two week the rate decrease

- Clearly visible the moment when automatic Software Recovery was disabled

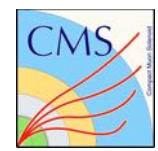
BPix Fraction of Dead ROC (%)



FPix Fraction of Dead ROC (%)



- Total fraction of inactive ROC now $\sim 11\%$



Conclusion from statistical analysis

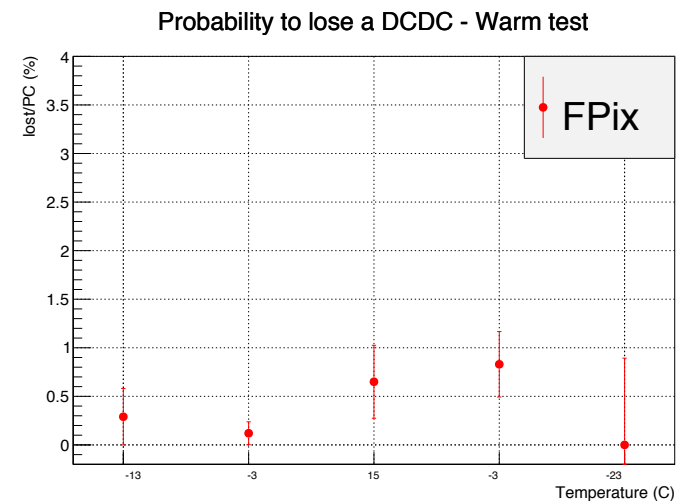


- No correlation between the number of power cycle and broken DCDC
 - All the DCDC have experienced almost the same number of power cycle (mainly in April/May)
- No patterns in the distribution of the broken DCDC converters
- The failure rate per power cycle almost steady
 - Cause is not radiation or (unsafe) operations ?

1. Understand the source of the problem
 - Main goal is to stop the problem
 - No success → Detector will be extracted
 - Find some hints in order to understand where to look once the detector will be out
 - Check all the procedure for 2018
2. Finish the 2017 data taking in good condition
 - Keep the number of power cycle as low as possible
3. Assumptions (continuously stressed)
 - Problem on DCDC board
 - Common component of Bpix and Fpix
 - Also not connected DCDC failures
 - Module not compromised by these failures
 - Everything works fine on recovered DCDC modules
 - Module cannot be replaced

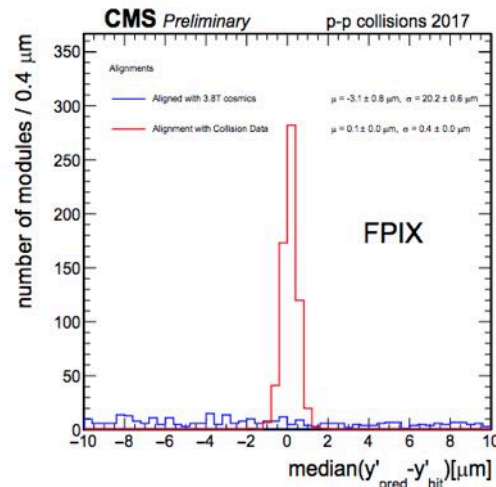
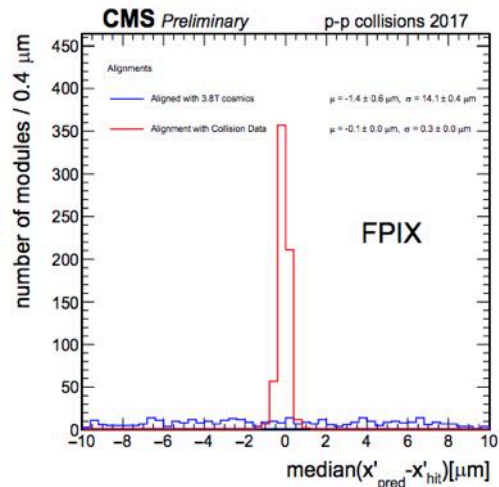
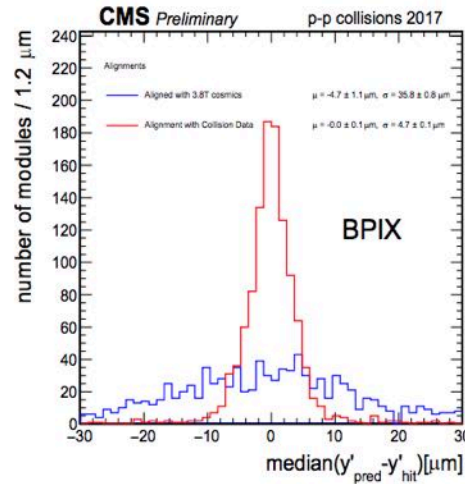
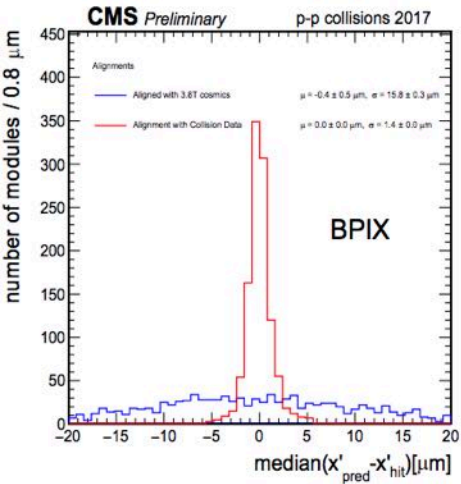
- Something change on October 5th
 - Nothing has been identify
- Blow fuse at DCDC input
 - Evidences exclude this
- Overvoltage at DCDC input
 - ASIC could break
 - DCDC failure reproduced in lab only with OV
- Failure of components on DCDC board
 - Test ongoing
- Mechanical failure
 - Not compatible with recovered DCDC
 - Any kind of short should blow the fuse or trigger power supply protection
- Problem in the DCDC enable line form CCU
 - Not obvious how this can break DCDC
 - No anomaly observed due to radiation or GND level differences
- Noise in/from power system
 - No evidence on both Lab and UXC
- External causes
 - Radiation, high luminosity
 - No changes on failure rate
 - Magnetic field
 - No evidence from Lab test inside magnetic field

- Try to understand what is broken
 - DCDC converter IV curves of several power groups
- Monitor the input voltage on DCDC
 - DCDC chip designers suggest to check for Over Voltage
 - Installed scopes to monitor power supply outputs during dis/en-able cycles: no anomaly observed
- Modify conditions to modify failure rate
 - Statistical analyses
 - Reduced input voltage (11V→9V) in 50% analog converters
 - No failure of ANY analog converters since then...
- Some DCDC on Bpix are unused, stress test on those
 - ~500 dis/en-able cycles: no failure
- Stress test of four DCDC converter sets (8 converters) in FPIX
 - One failure after ~250 power cycles (for each converter), digital converter
 - after ~3300 power cycles no other failure show up
- Failure rate measured at different temperatures
 - Failure rate per power cycle close to the one observed in standard conditions **in the first 30 days**

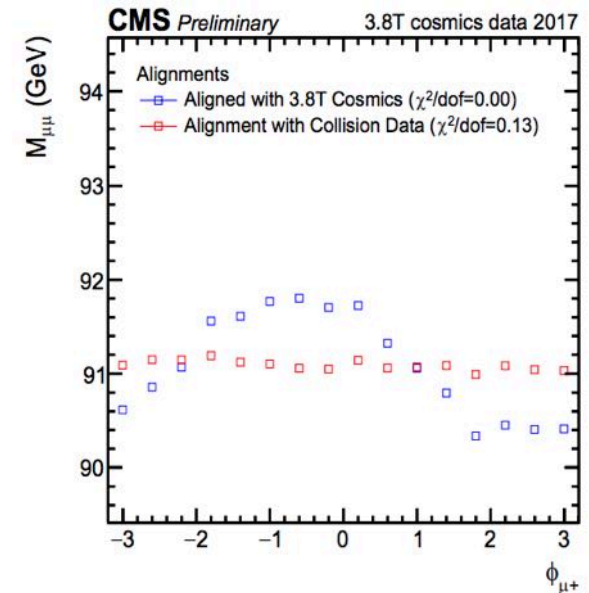


- A lot of different tests in Lab
 - Try to reproduce the failure
 - Very frequent dis/en-abling sequence
 - No failure up to 1000's cycles and passive loads
 - No failure up to 100's cycles and real modules
 - Look for anomalies (spikes, oscillations...) in the power system
 - Nothing observed
 - DCDC behavior inside magnetic field (3T)
 - No failure observed with 500Hz dis/en-able cycles and different orientations
 - Radiation
 - Old results on irradiated converter show no anomalies
 - New irradiation with X-rays (1.5Mrad, CMSx2) has the some conclusions (same chip but different boards)

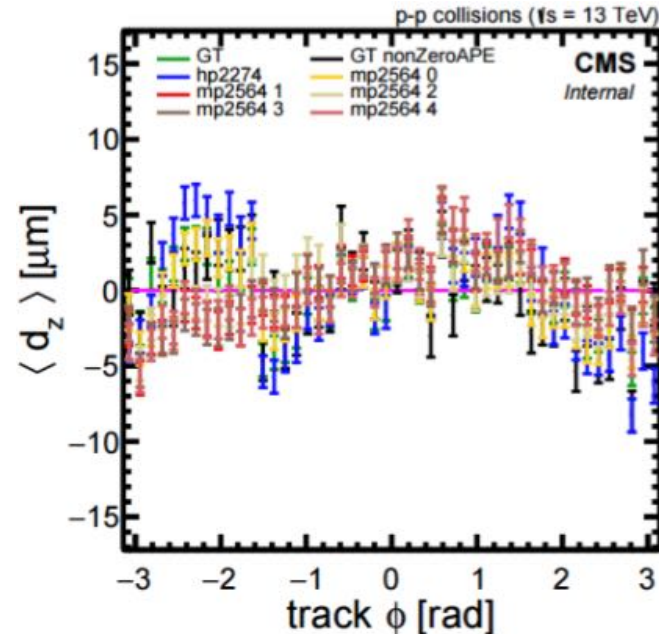
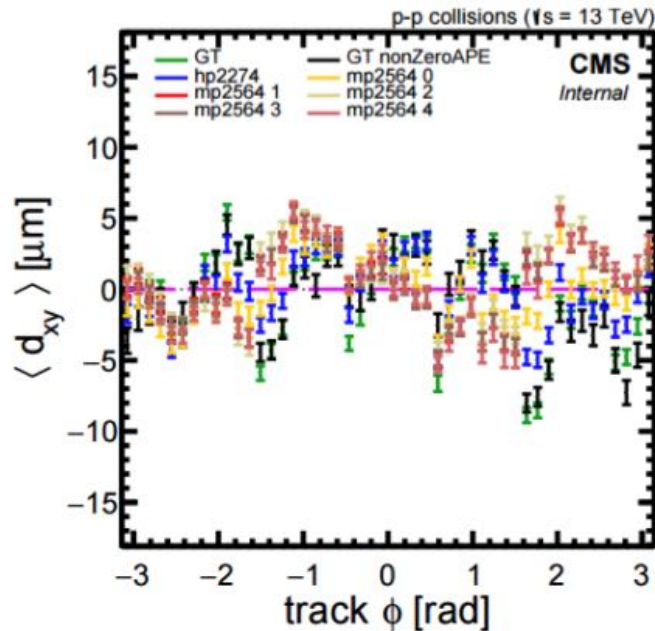
- Fast dis/en-abling sequence (enabling before voltage is 0)
 - No failure
- Back power from neighbour DCDC
 - No failure
- Anomalous signal on enable line
 - No failure
- Attempt to break DCDC
 - Only two possible scenarios found up to now
 - Input voltage exceed 17-18V
 - Input capacitor removed (or damaged)



- Many alignment campaigns
- Intrinsic resolution reached very soon



- Primary Vertex

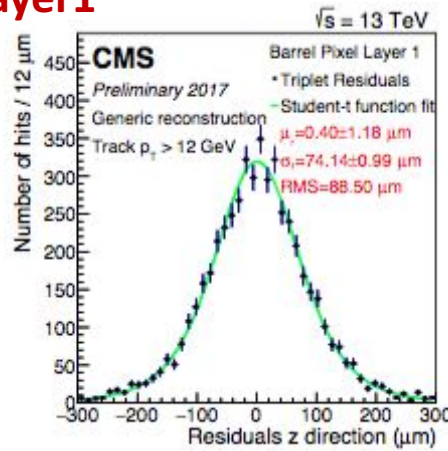
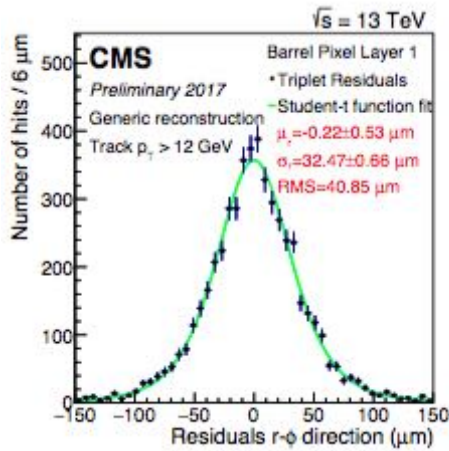


- Position of PV as a function of track coordinates is very sensible to the pixel part of the tracker
- PV performance got a lot of improvement during the year

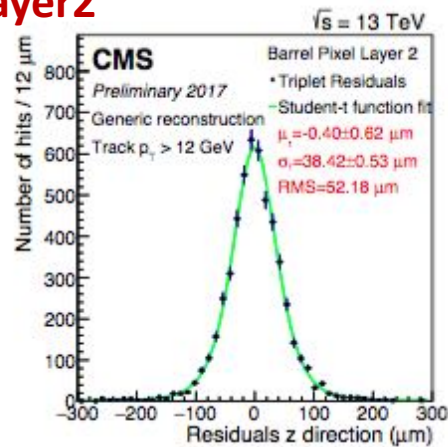
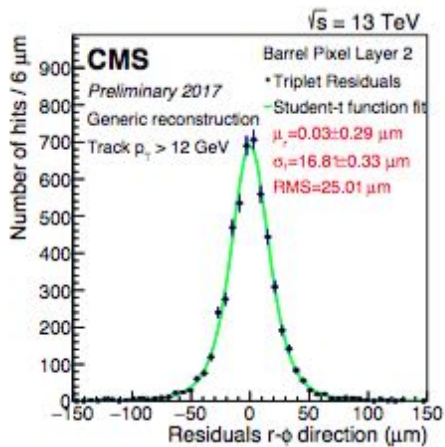
Performances: Hit Resolution



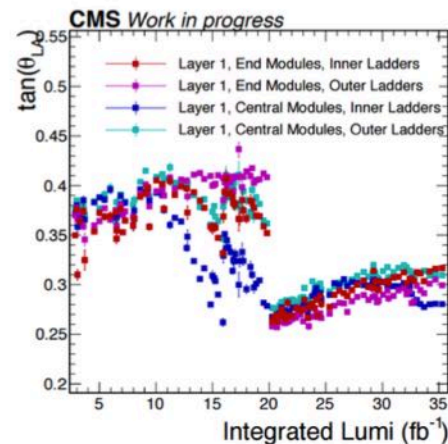
Layer1



Layer2

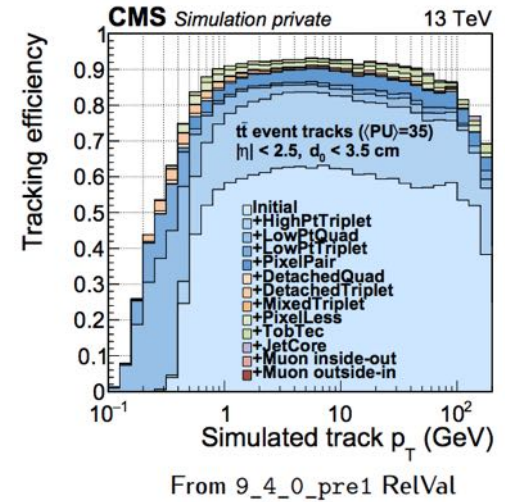


- Layer 2-4 and Fpix good MC matching and as expected resolution
- L1 ~50% worse than expected
 - Reproduced by MCv2 with increased threshold
 - Present challenge



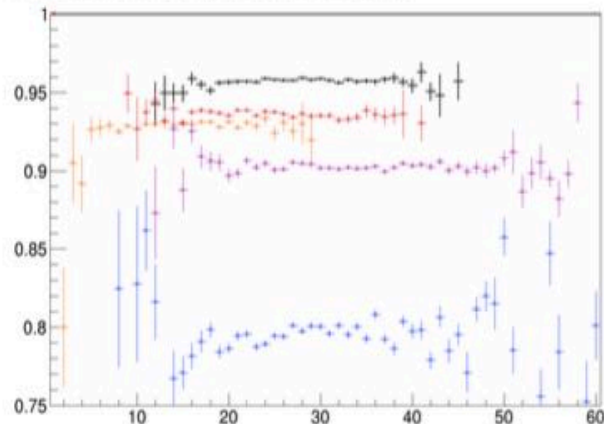
- Changes on L1 HV affect Lorentz Angle
- Impact on clusters position

- Despite the not optimal performance of BPIX1 and the larger than expected number of inactive components, Physics in 2017 is not compromised
 - Mitigations already in place, more foreseen
 - Performance better than 2016 even in the toughest conditions
 - Improvements expected with ultimate alignment and calibration

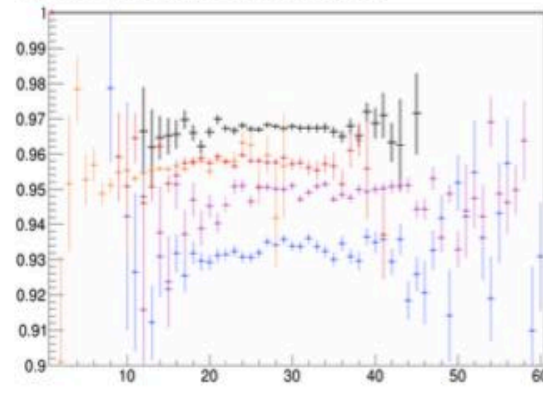


MC ttbar PU=35
 Run 283408 PU~35
 Run 299649 PU~40
 Run 302553 PU~30
 Run 302597 PU~20

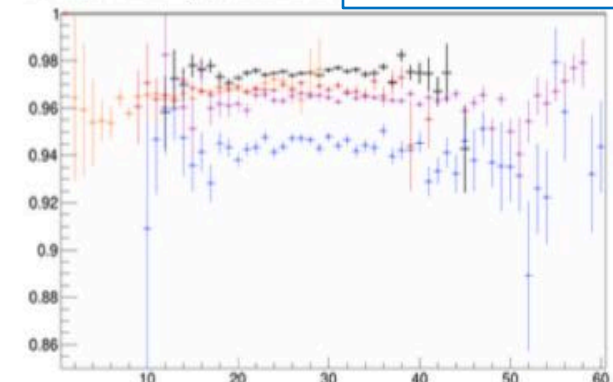
PXB Layer1 Efficiency vs GoodNumVertices



PXB Layer2 Efficiency vs GoodNumVertices



PXF Layer1 Efficiency vs GoodNumVertices

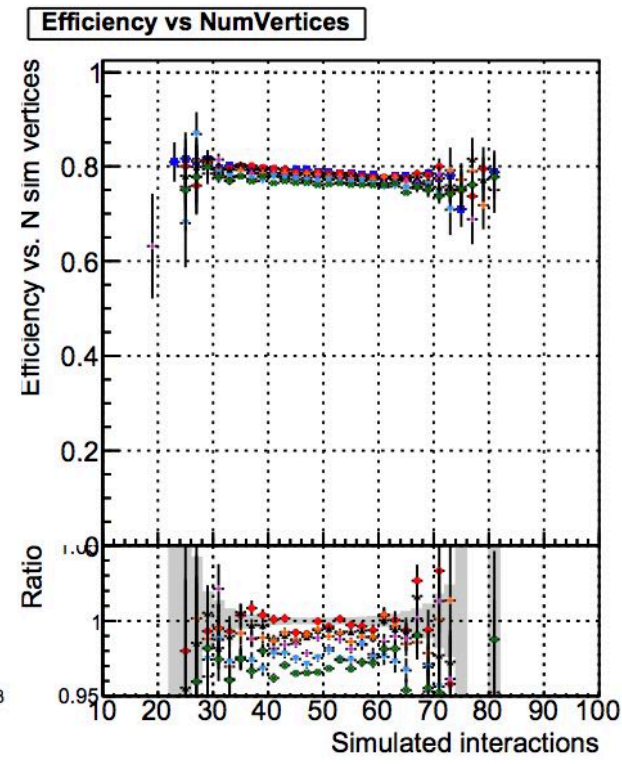
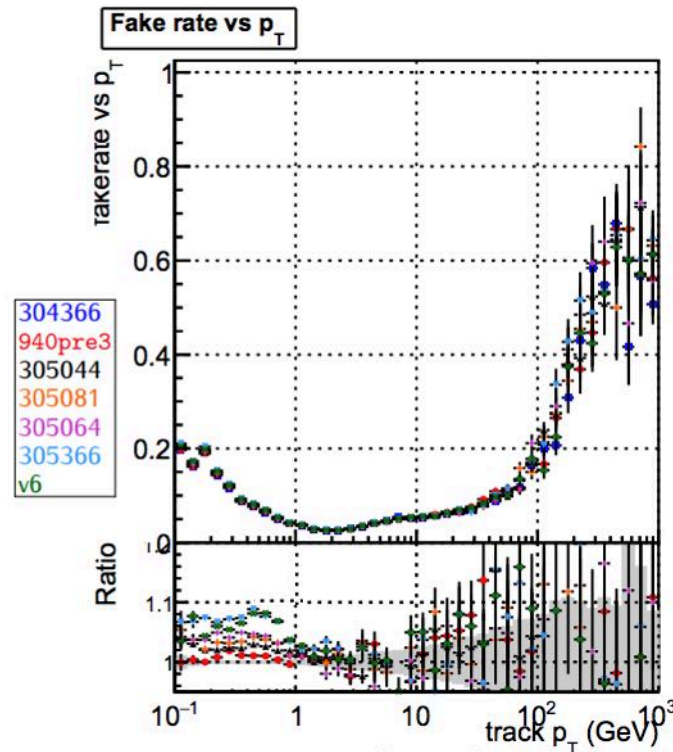
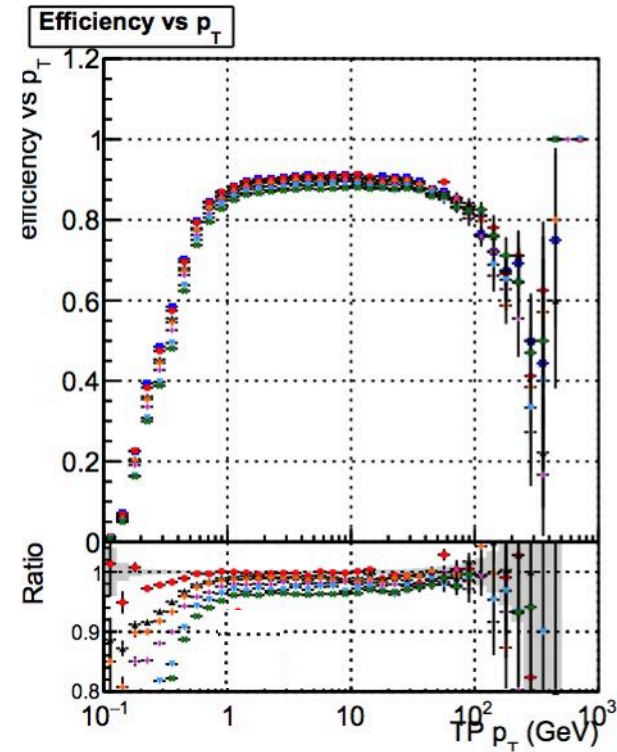


V. Innocente, CMS Week

- Tracking and BTV POG are working on estimates and corresponding plots derived by simulations
 - Also others POG are working on the Pixel failure impact (not reported here)

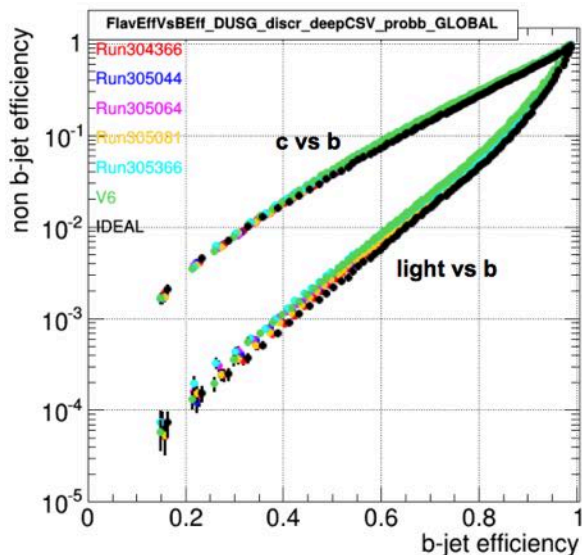
- Some preliminary results shown here
 - ttbar ReVal
 - Scenarios from data
 - Run 304366 : reference
 - Run 305044 : Permanently BAD DCDC
 - Run 305064 : Large overlap hole in Fpix
 - Run 305081 : Two FEDs with errors
 - Run 305366 : Highest number of BAD components
 - V6 : estimated 2017 end scenario

 - Maps in backup



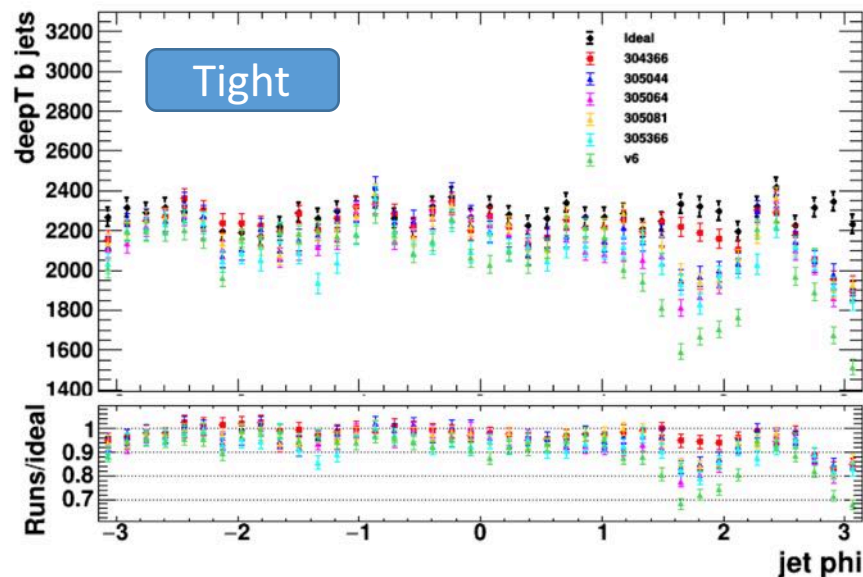
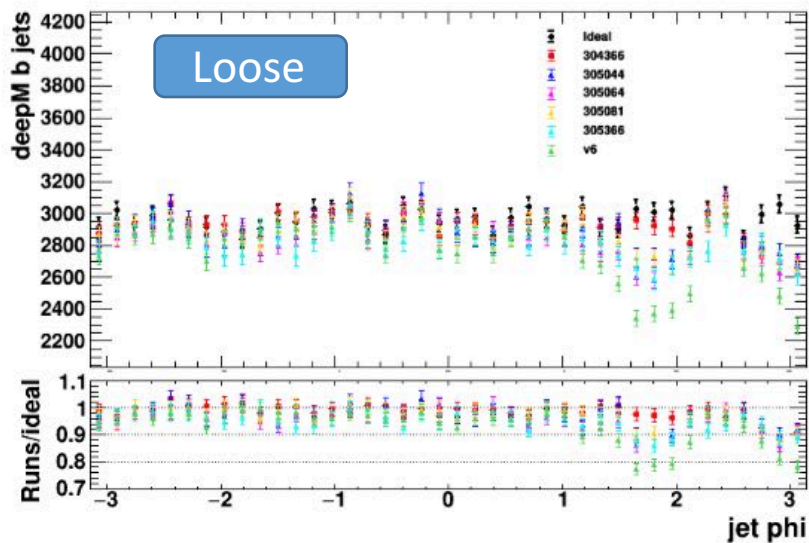
- Overall efficiency decrease by up to 4% with a increase on fake rate up to 3%
- Vertex efficiency decreases by up to 3 %
- Also IP resolution and Vertex resolution are affected

M. Kortelainen



- Impact of DCDC issue on b-tagging efficiency is present
 - Some region on ϕ more affected

C. Collard

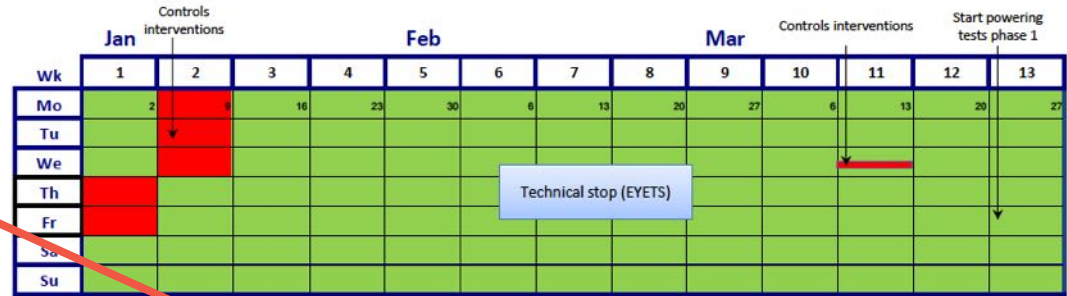


- Needed to understand the cause of (and the solution to) the problem and repair the broken DCDC converters
- Requested one week earlier start of YETS to extract FPIX+ before Christmas
- In meantime some work on DCDC to be ready for replacement
 - Change the input fuse on DCDC spares:
 - 1.5A --> 4A (Digi) 3A (Ana)
 - Input voltage could me further decreased
 - Build new DCDC with the available componets
 - 4A/3A fuses and 25V capacitors

- Very challenging year for new Pixel detector
- Faced different issues from commissioning to DCDC problem
 - A working solution for almost everything has been addressed
 - DCDC converters issue is the most problematic and the most difficult to face
 - Constant work during the last 2 month
 - Cause not yet understood, tests still ongoing
 - Detector extraction during YETS with two main focus
 - Understand what has been broken
 - Apply some modifications to have a safe 2018
 - Impact on tracking, b-tagging, physics still under study
- Detector performances during 2017 have been good (at least up to October 5th) and they have a continuous improvement during the year
- Plans to replace Layer1 modules (new sensors, new TBM, new PROC600) during LS2

Backup

Commissioning : Timing Scan



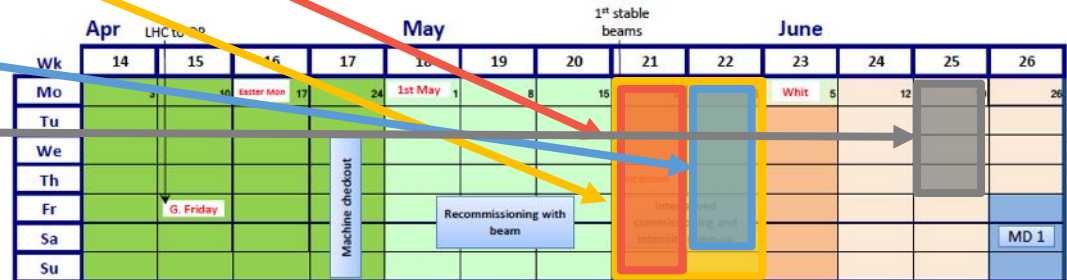
Strip time adjustment completed

BPIX L3-L4 and FPIX time adjustment completed

1st attempt BPIX L1-L2 timing

2nd attempt BPIX L1-L2 timing

Final BPIX L1-L2 timing



- Last timing scan performed at the end of October (150b fill)
 - Setting confirmed



Commissioning: Detector Tuning



BPIX L1 HV → 200V

BPIX L2 HV bias → 250V to improve timing

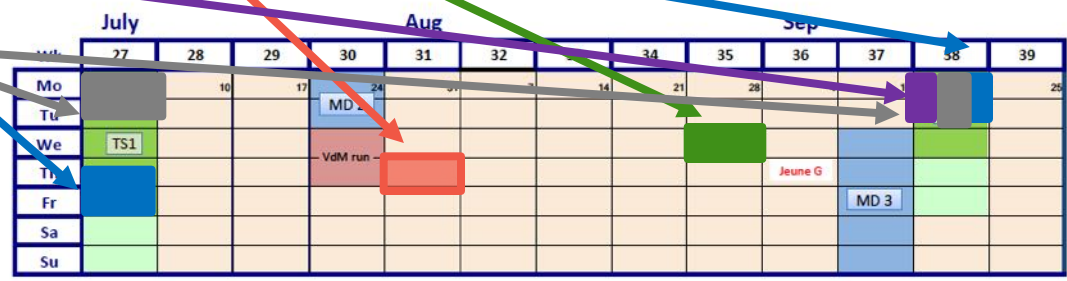
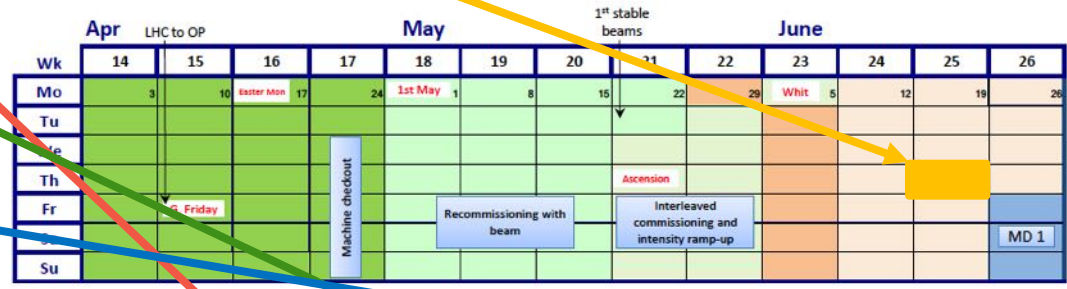
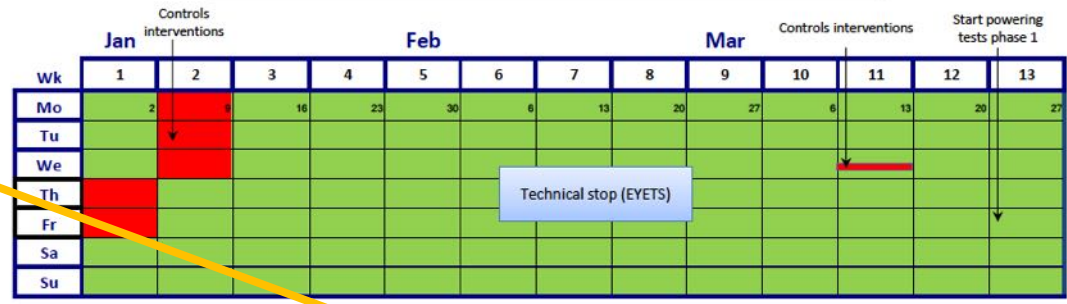
Pixel HV bias increase to compensate rad effects:

- BPIX L1 → 350V
- BPIX L3-L4 → 200V
- FPIX → 300V

FPIX thresholds retuning

BPIX thresholds: L1 thresholds reduced by ~15%

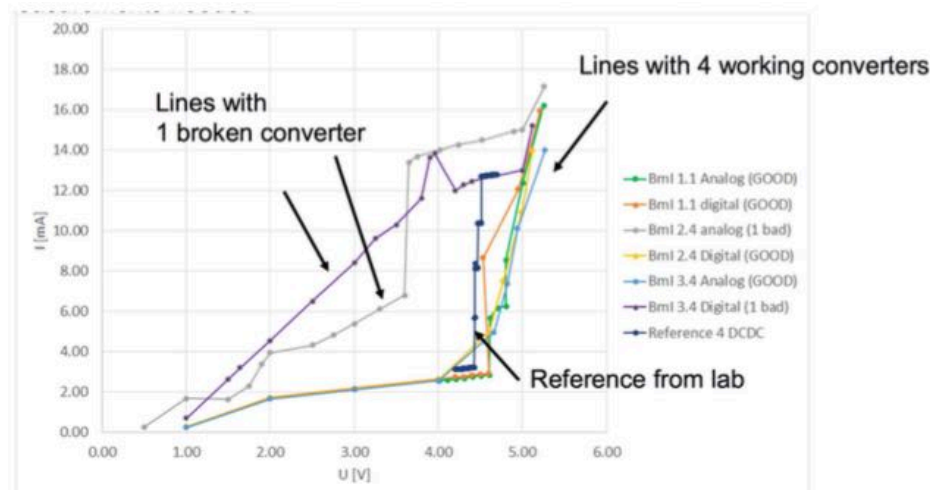
BPIX pulse height and gain calibration



S

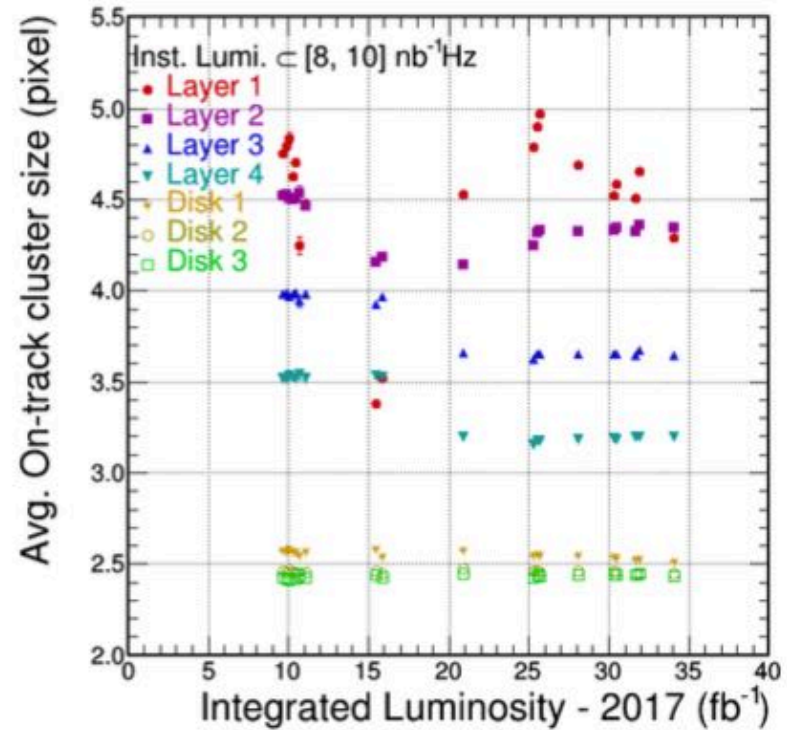
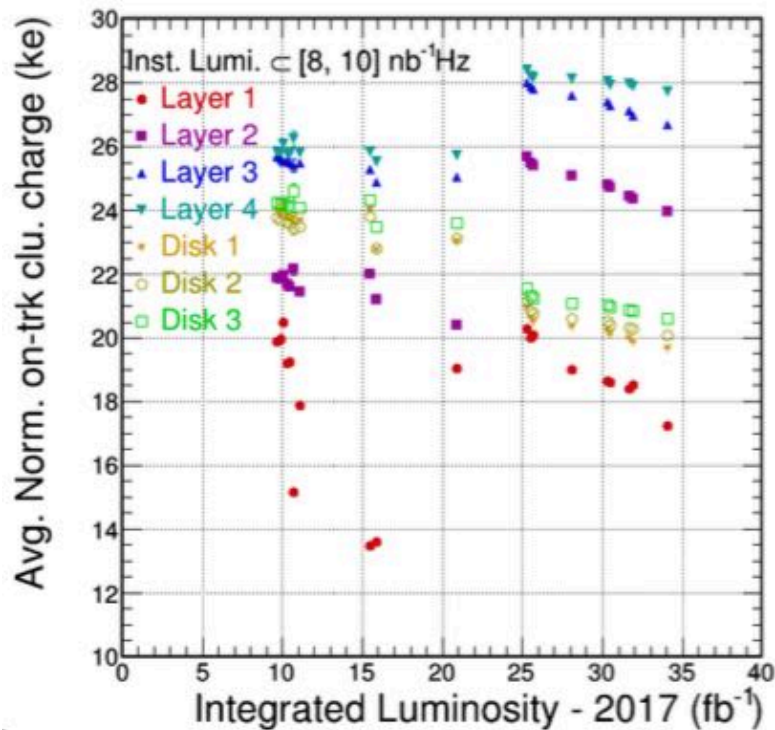
- Continuous balance between higher detector efficiency, higher uptime, and lower dead time
 - Introduced periodic (70Hz/100Hz) ROC reset to mitigate dynamic inefficiency
 - Unavoidable dead time to readout the pipelines before the reset: reduced to 0.7% from 1.3%
 - New Soft Error Recovery procedure
 - Negligible dead/downtime (at $L \sim 10^{34} \text{cm}^{-2} \text{s}^{-1}$)
 - With old procedure about 1-2% dead time (at $L \sim 1.5 \cdot 10^{34} \text{cm}^{-2} \text{s}^{-1}$)
 - Power cycle took ~ 5 minutes, now $\sim 20-30$ seconds
 - Optimized detector configurations (Pixel+Strip) when HV is on
 - Reduced by 50% by performing a single pause and resum
 - Pixel configuration now in parallel: pause and resume reduced to only 5 seconds

- FEAST2 designers suggested to measure the IV curve to see the DCDC linear regulator switch on
 - Voltage on DCDC from 0 to 4.7V (output not enable)
 - Every linear regulator should drain 3mA

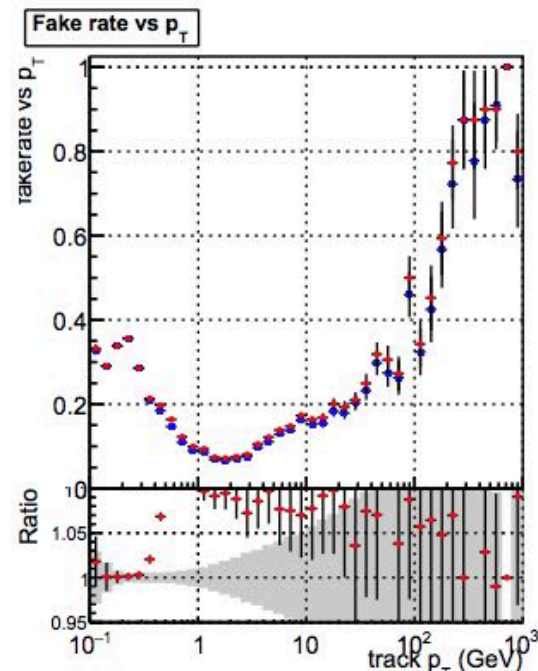
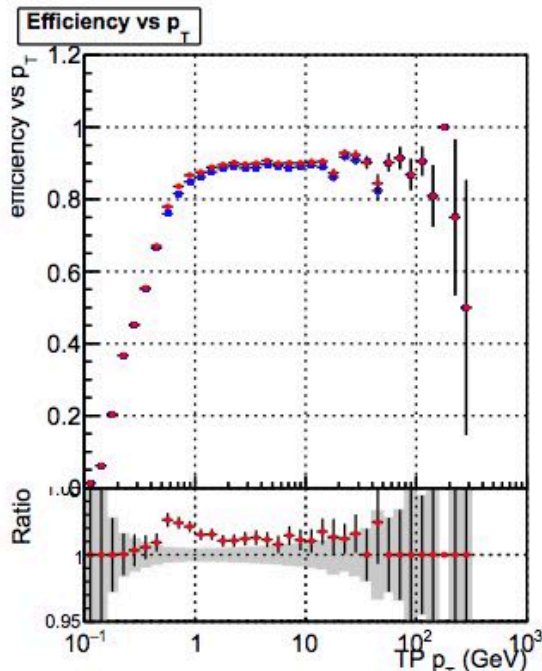


- When all DCDC converter are good the behavior is as expected
- When there are broken DCDC an ohmic behavior show up
 - Similar behavior of lab DCDC broken with over voltage

- Charge Collection
 - Loss of charge collection efficiency probably due to radiation damage

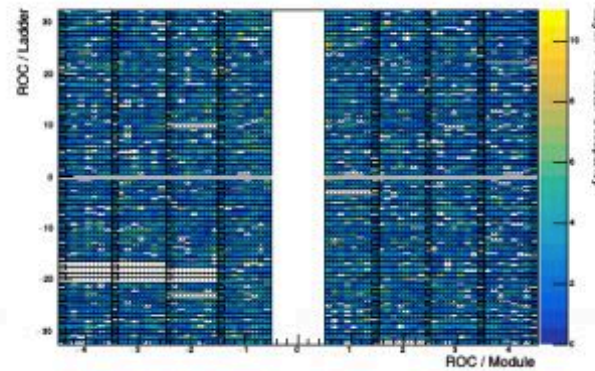
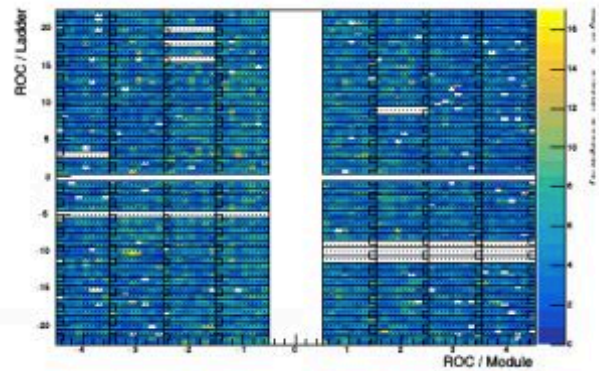
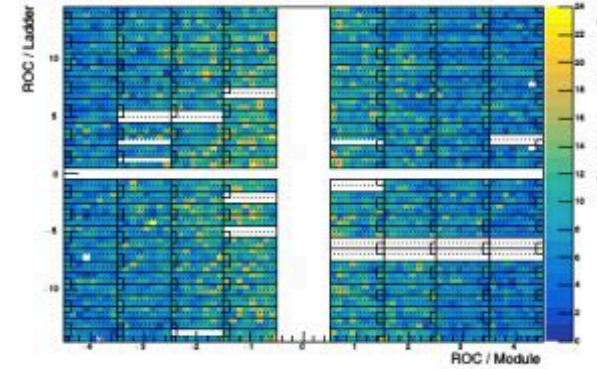
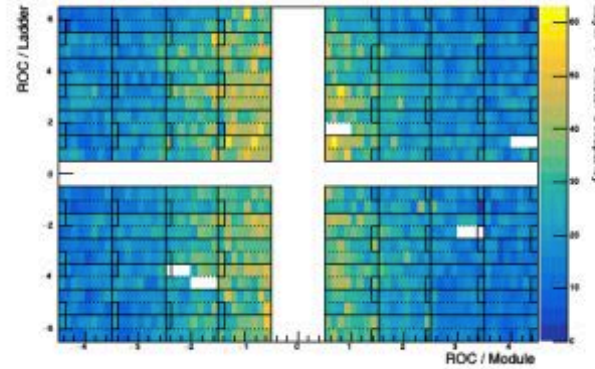
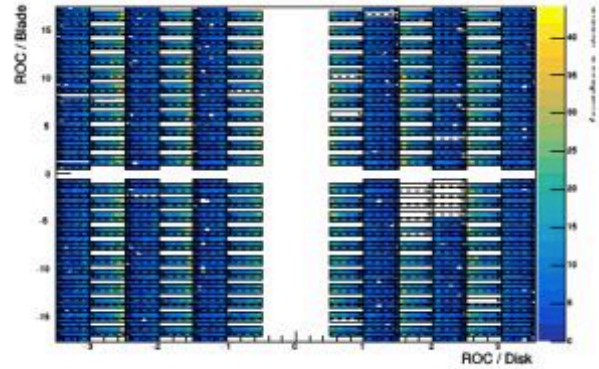


- Preliminary test to automated PixelPair mitigation
 - PixelPair originally used to cover BPix-FPix transition region covered only by 3 layers and the region with inactive areas in BPix layers 2 and 3

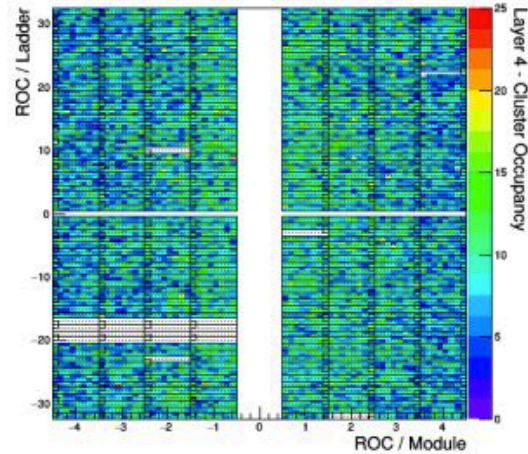
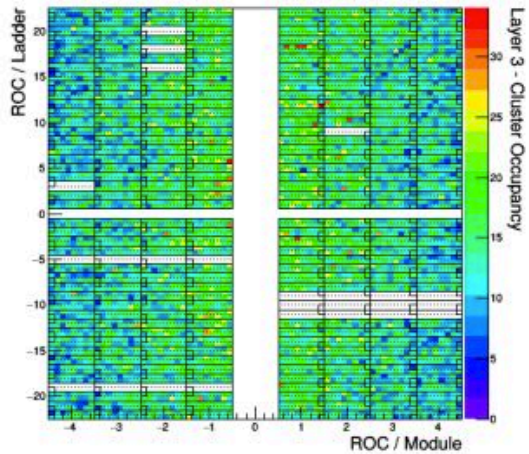
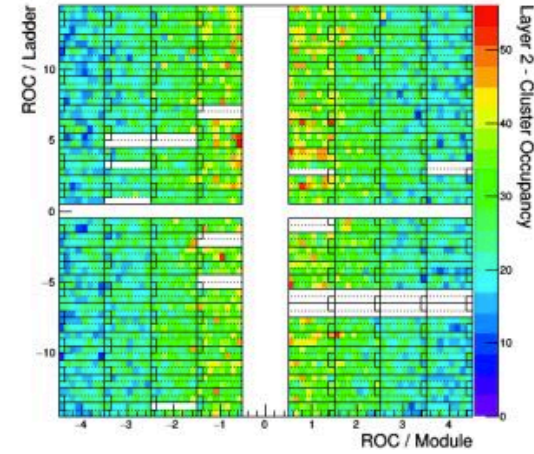
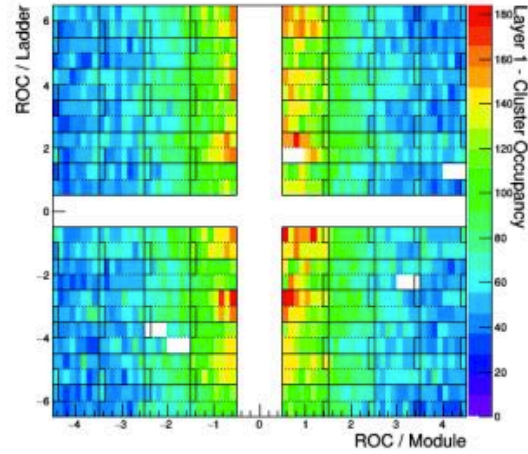
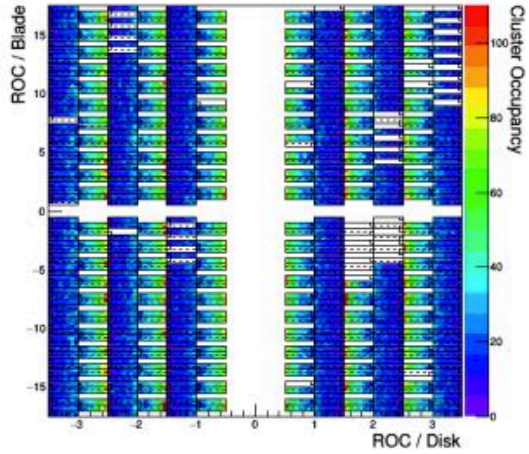


M. Kortelainen

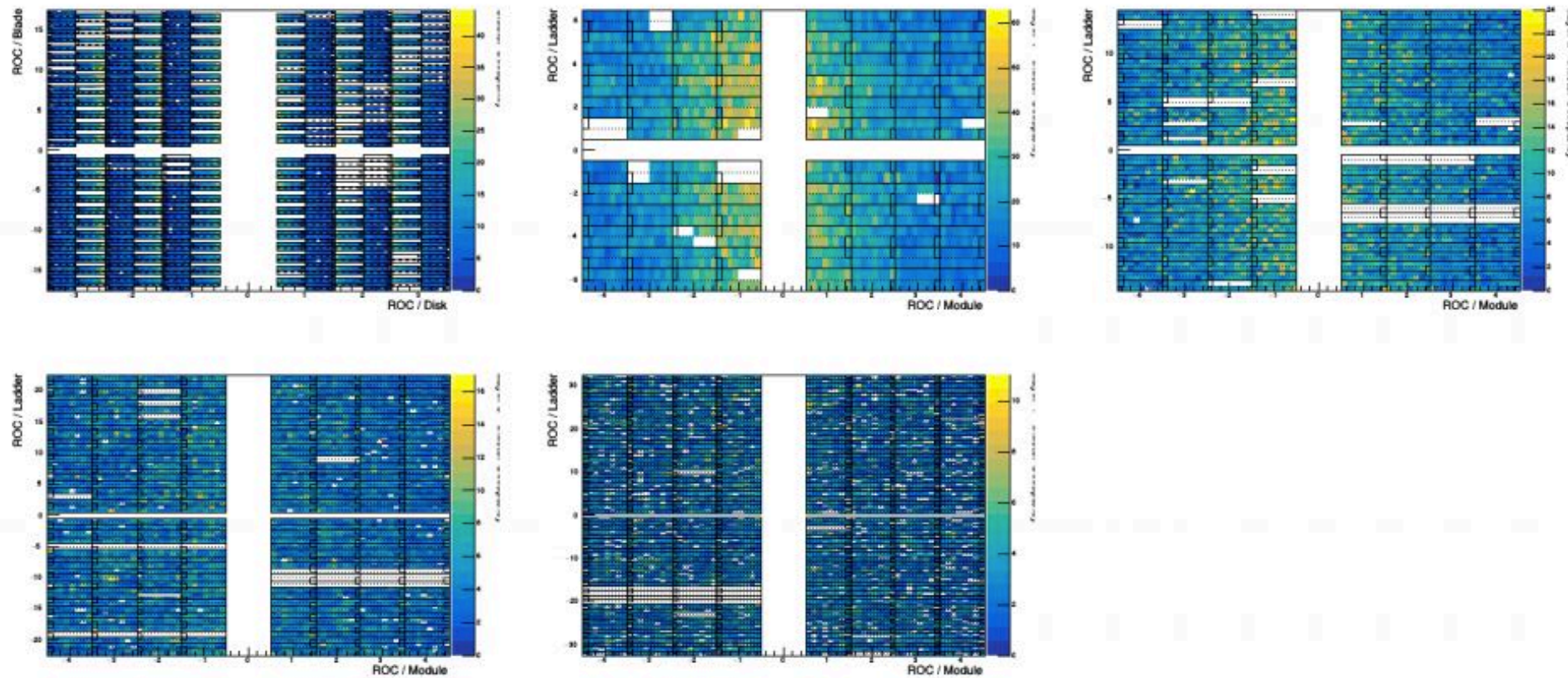
- Noticeable improvement
 - Big part of the PixelPair improvement goes to reduction of strip seeds



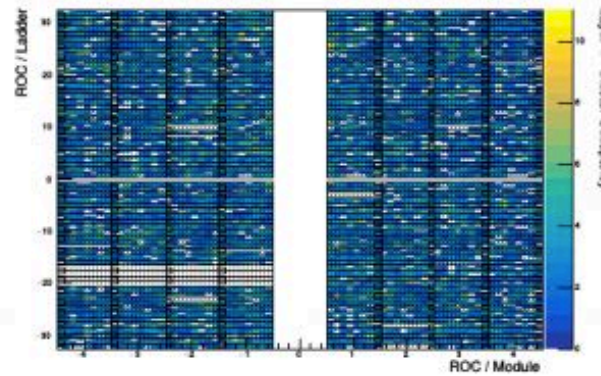
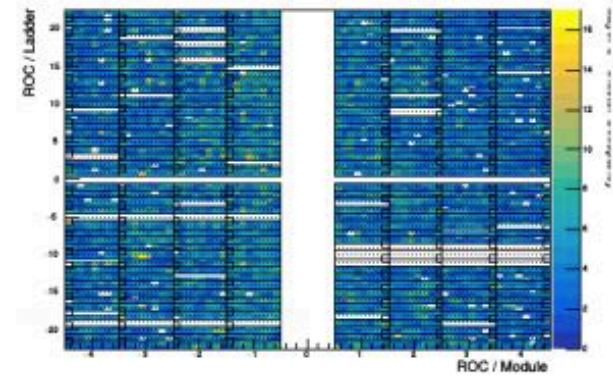
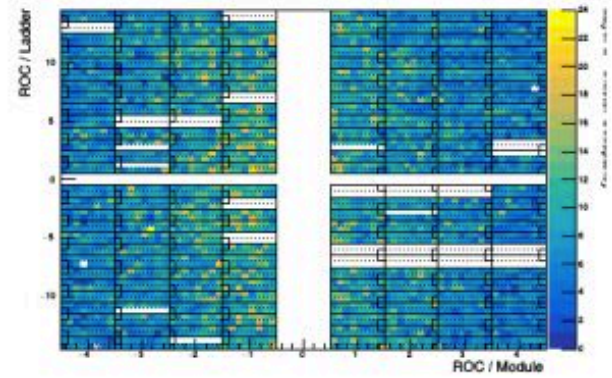
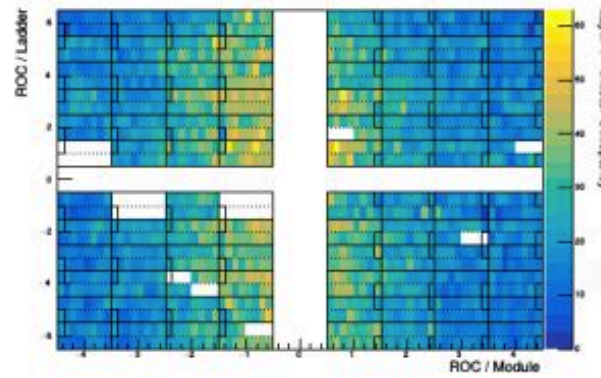
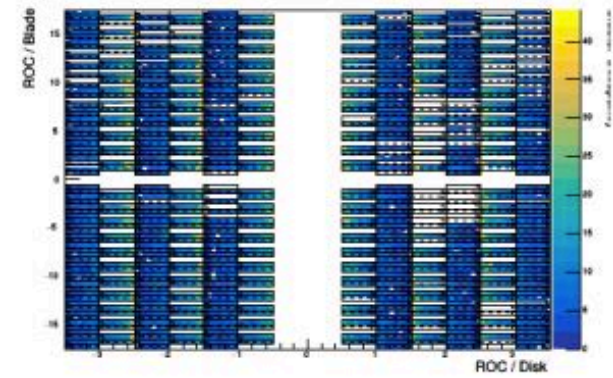
- October 4th



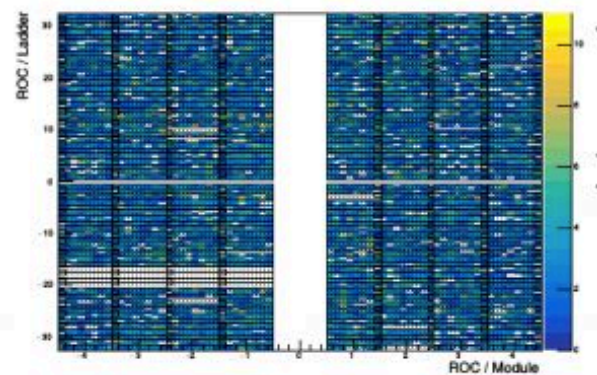
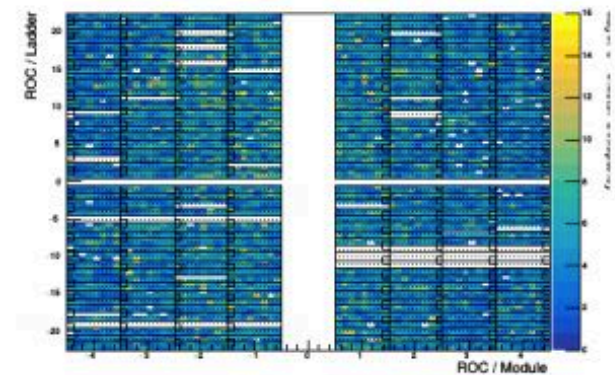
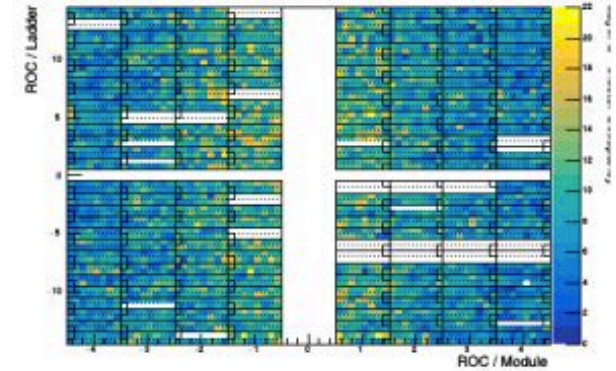
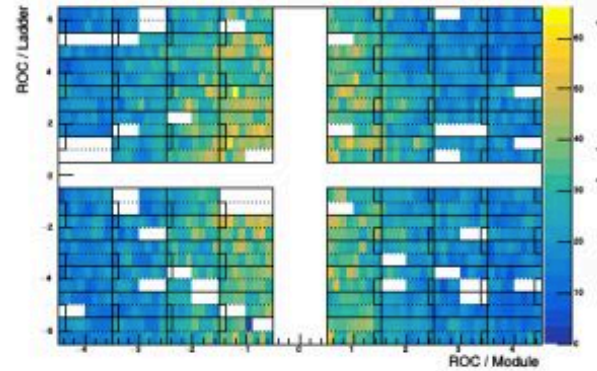
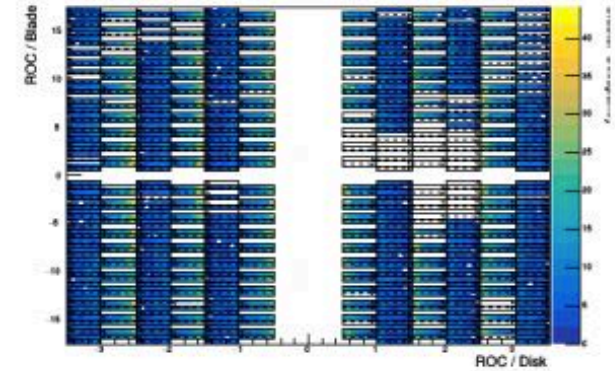
- SiPixelQuality v10



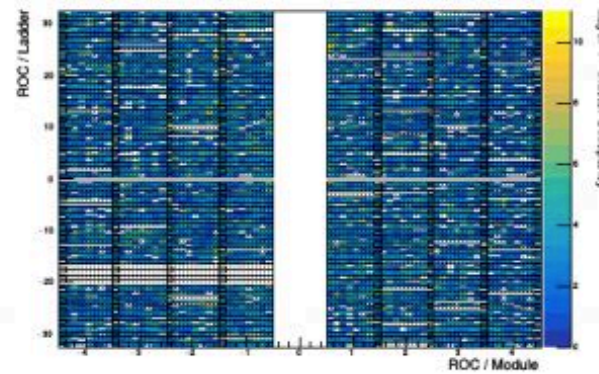
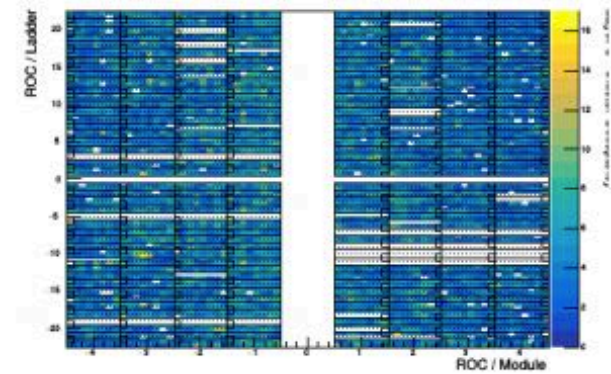
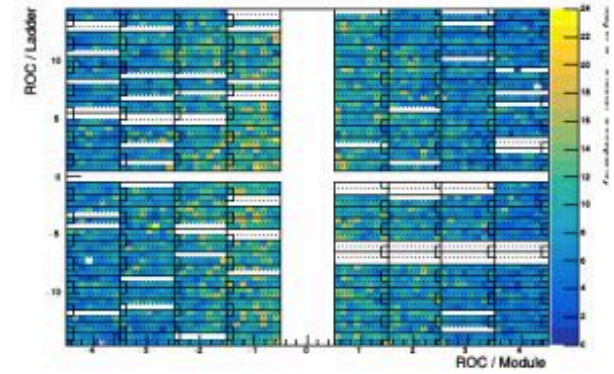
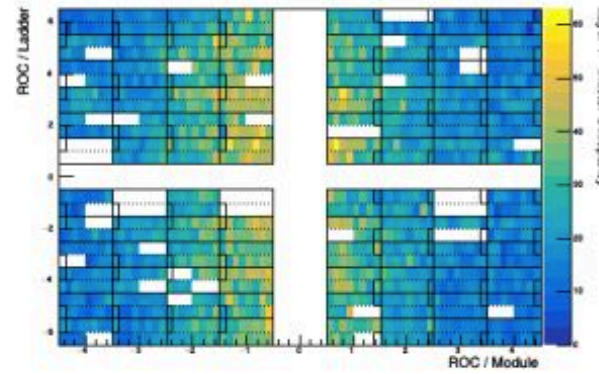
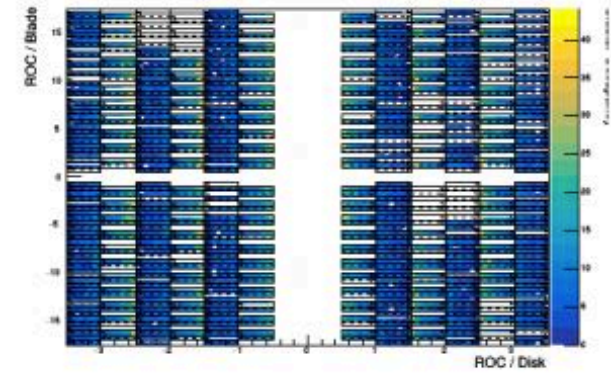
- October 13th



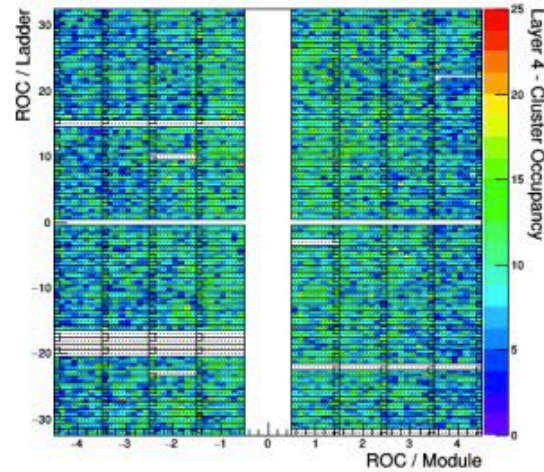
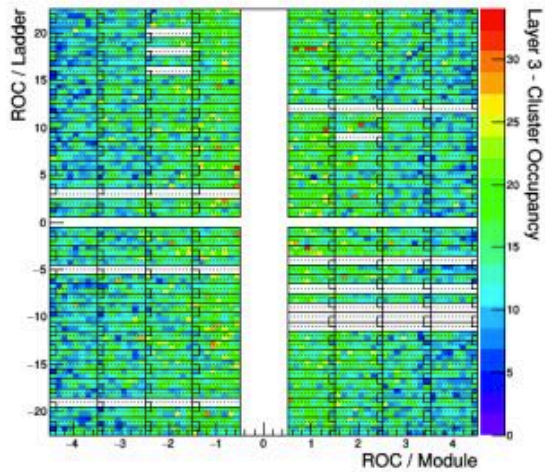
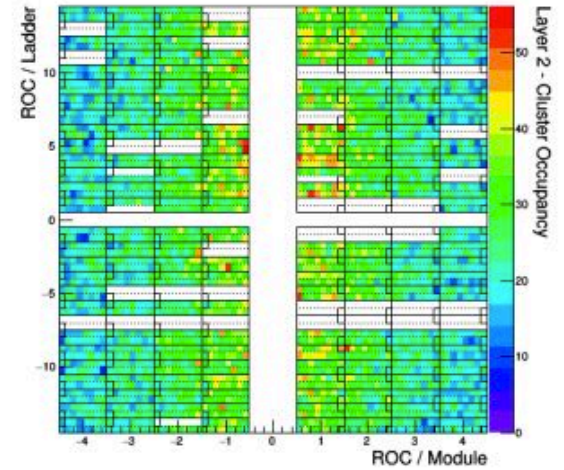
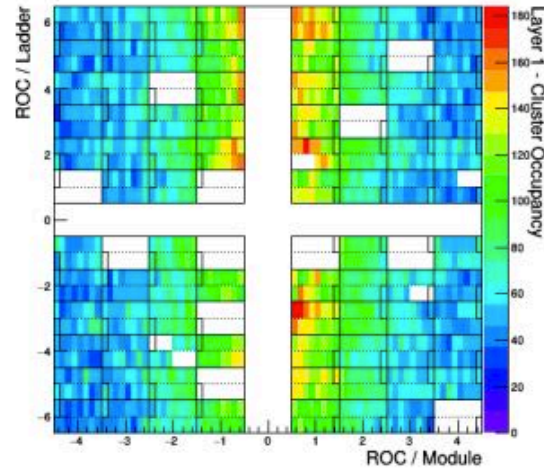
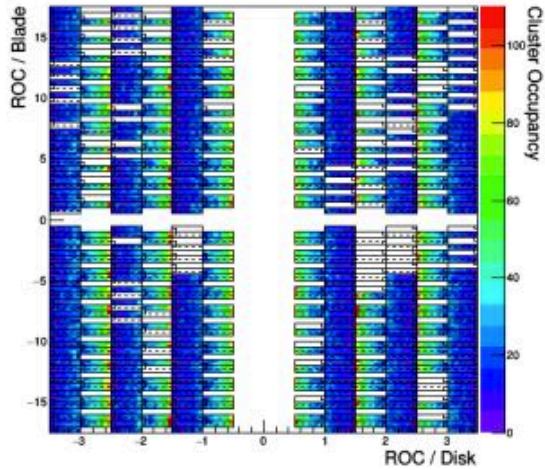
- October 15th



- October 15th



- October 21th



- (gu)Es(s)timated 2017 end

- Dec 22nd FPIX+ (2 quadrants) is extracted
 - US crew will be present
- Dec 22nd-23rd : broken DCDC converter(s) will be investigated
 - Aachen team at CERN, US crew, possibly FEAST designers
- Dec 27th-29th: tests and investigations of converters and one FPIX+ quadrant. Dismantling of the DCDC converters from 2nd quadrant
- Jan 2nd-20th: continue investigation, reworking and testing of FPIX+
- Jan 20th: BPIX and FPIX- are extracted
- ~Jan 20th: reworking of DCDC converters from the detector
 - Technician(s) from the company working at P5
- Jan 20th- Feb 4th: investigation, reworking, and testing of FPIX- and BPIX
- Feb 5th – 12th : reinstallation starts
- To be noted
 - The plan depend heavily on the findings when the first DCDC converters are available
 - BPIX and FPIX- will be repaired in parallel in the two labs at P5: second lab being prepared now.